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### Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

### Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

#### Details

Product Status	Obsolete
Number of LABs/CLBs	848
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	131
Number of Gates	6000
Voltage - Supply	4.5V ~ 5.5V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 70°C (TA)
Package / Case	160-BQFP
Supplier Device Package	160-PQFP (28x28)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/microsemi/a1460a-1pqg160c">https://www.e-xfl.com/product-detail/microsemi/a1460a-1pqg160c</a>

# 1 – ACT 3 Family Overview

## General Description

Microsemi's ACT 3 Accelerator Series of FPGAs offers the industry's fastest high-capacity programmable logic device. ACT 3 FPGAs offer a high performance, PCI compliant programmable solution capable of 186 MHz on-chip performance and 9.0 nanosecond clock-to-output (–1 speed grade), with capacities spanning from 1,500 to 10,000 gate array equivalent gates.

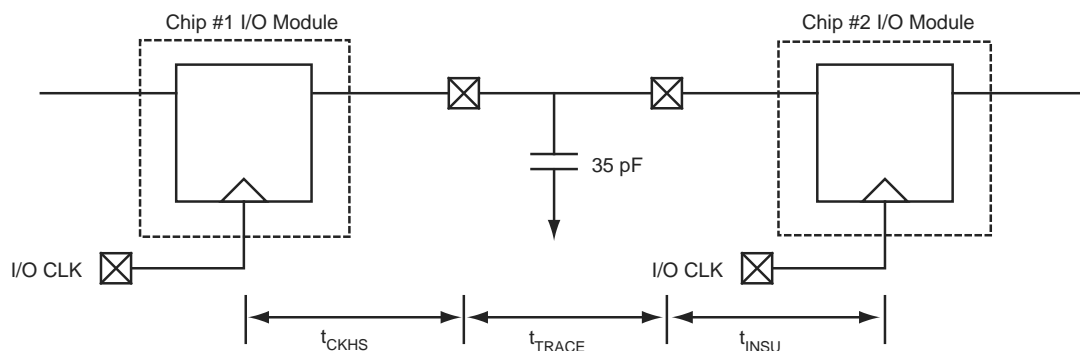
The ACT 3 family builds on the proven two-module architecture consisting of combinatorial and sequential logic modules used in Microsemi's 3200DX and 1200XL families. In addition, the ACT 3 I/O modules contain registers which deliver 9.0 nanosecond clock-to-out times (–1 speed grade). The devices contain four clock distribution networks, including dedicated array and I/O clocks, supporting very fast synchronous and asynchronous designs. In addition, routed clocks can be used to drive high fanout signals such as flip-flop resets and output.

The ACT 3 family is supported by Microsemi's Designer Series Development System which offers automatic placement and routing (with automatic or fixed pin assignments), static timing analysis, user programming, and debug and diagnostic probe capabilities.

Accumulators (16-Bit)	47 MHz
Loadable Counters (16-Bit)	82 MHz
Prescaled Loadable Counters (16-Bit)	186 MHz
Shift Registers	186 MHz

**Figure 1-1 • Predictable Performance (worst-case commercial, –1 speed grade)**

## System Performance Model



## Power Dissipation

$$P = [ICC_{\text{standby}} + I_{\text{active}}] * VCC * IOL * VOL * N + IOH * (VCC - VOH) * M$$

EQ 3

where:

ICC standby is the current flowing when no inputs or outputs are changing

Iactive is the current flowing due to CMOS switching.

IOL and IOH are TTL sink/source current.

VOL and VOH are TTL level output voltages.

N is the number of outputs driving TTL loads to VOL.

M equals the number of outputs driving TTL loads to VOH.

An accurate determination of N and M is problematical because their values depend on the design and on the system I/O. The power can be divided into two components: static and active.

## Static Power Component

Microsemi FPGAs have small static power components that result in lower power dissipation than PALs or PLDs. By integrating multiple PALs/PLDs into one FPGA, an even greater reduction in board-level power dissipation can be achieved.

The power due to standby current is typically a small component of the overall power. Standby power is calculated in Table 2-9 for commercial, worst case conditions.

**Table 2-9 • Standby Power Calculation**

ICC	VCC	Power
2 mA	5.25 V	10.5 mW

The static power dissipated by TTL loads depends on the number of outputs driving high or low and the DC load current. Again, this value is typically small. For instance, a 32-bit bus sinking 4 mA at 0.33 V will generate 42 mW with all outputs driving low, and 140 mW with all outputs driving high. The actual dissipation will average somewhere between as I/Os switch states with time.

## Active Power Component

Power dissipation in CMOS devices is usually dominated by the active (dynamic) power dissipation. This component is frequency dependent, a function of the logic and the external I/O. Active power dissipation results from charging internal chip capacitances of the interconnect, unprogrammed antifuses, module inputs, and module outputs, plus external capacitance due to PC board traces and load device inputs.

An additional component of the active power dissipation is the totem-pole current in CMOS transistor pairs. The net effect can be associated with an equivalent capacitance that can be combined with frequency and voltage to represent active power dissipation.

## Equivalent Capacitance

The power dissipated by a CMOS circuit can be expressed by EQ 4.

$$\text{Power } (\mu\text{W}) = C_{\text{EQ}} * VCC^2 * F$$

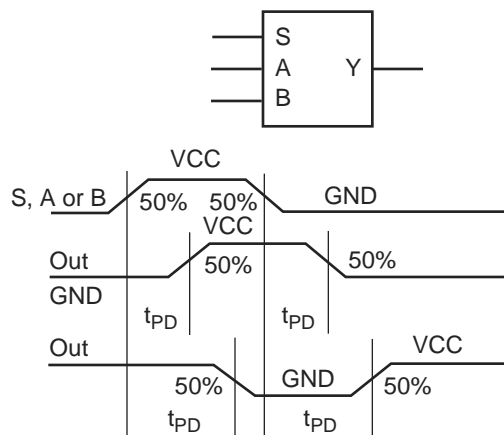
EQ 4

Where:

C<sub>EQ</sub> is the equivalent capacitance expressed in pF.

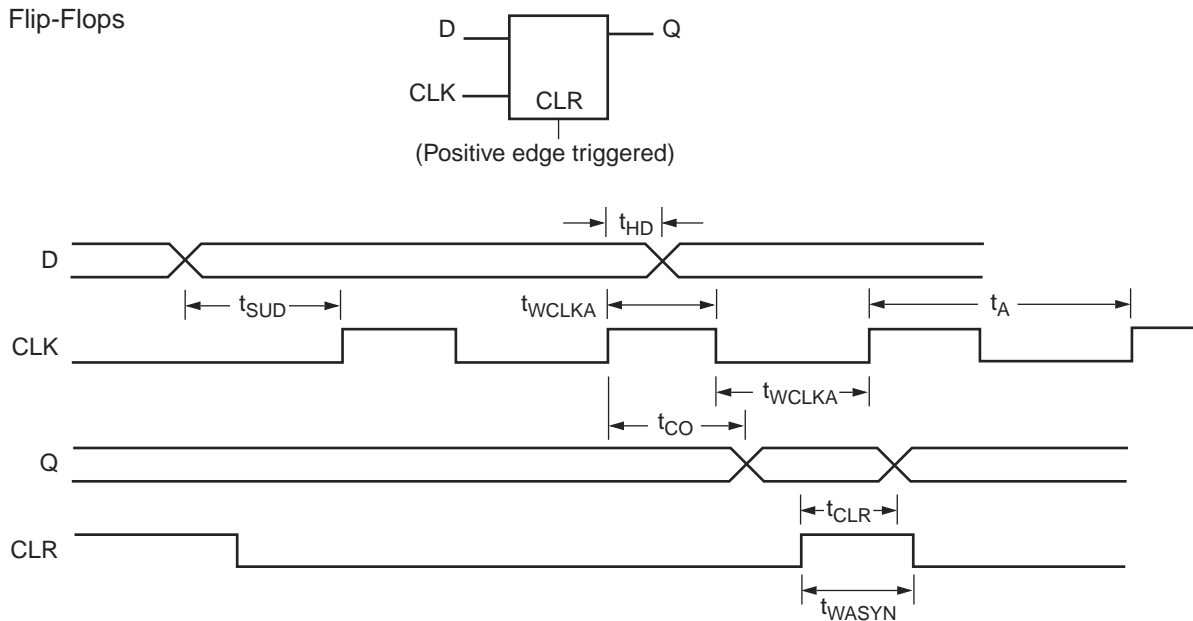
VCC is the power supply in volts.

F is the switching frequency in MHz.



**Figure 2-14 • Module Delays**

Flip-Flops



**Figure 2-15 • Sequential Module Timing Characteristics**

## Timing Derating

ACT 3 devices are manufactured in a CMOS process. Therefore, device performance varies according to temperature, voltage, and process variations. Minimum timing parameters reflect maximum operating voltage, minimum operating temperature, and best-case processing. Maximum timing parameters reflect minimum operating voltage, maximum operating temperature, and worst-case processing.

**Table 2-15 • Timing Derating Factor (Temperature and Voltage)**

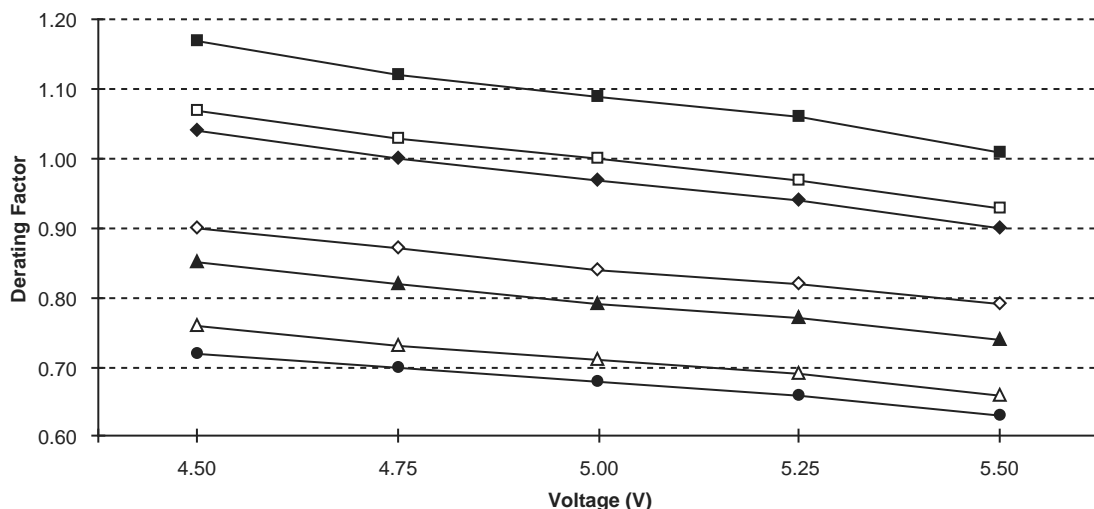
(Commercial Minimum/Maximum Specification) x	Industrial		Military	
	Min.	Max.	Min.	Max.
	0.66	1.07	0.63	1.17

**Table 2-16 • Timing Derating Factor for Designs at Typical Temperature ( $T_J = 25^\circ\text{C}$ ) and Voltage (5.0 V)**

(Commercial Maximum Specification) x	0.85
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**Table 2-17 • Temperature and Voltage Derating Factors (normalized to Worst-Case Commercial,  $T_J = 4.75\text{ V}$ ,  $70^\circ\text{C}$ )**

	-55	-40	0	25	70	85	125
<b>4.50</b>	0.72	0.76	0.85	0.90	1.04	1.07	1.117
<b>4.75</b>	0.70	0.73	0.82	0.87	1.00	1.03	1.12
<b>5.00</b>	0.68	0.71	0.79	0.84	0.97	1.00	1.09
<b>5.25</b>	0.66	0.69	0.77	0.82	0.94	0.97	1.06
<b>5.50</b>	0.63	0.66	0.74	0.79	0.90	0.93	1.01



Note: This derating factor applies to all routing and propagation delays.

**Figure 2-18 • Junction Temperature and Voltage Derating Curves (normalized to Worst-Case Commercial,  $T_J = 4.75\text{ V}$ ,  $70^\circ\text{C}$ )**

## A1425A, A14V25A Timing Characteristics (continued)

**Table 2-23 • A1425A, A14V25A Worst-Case Commercial Conditions, VCC = 4.75 V, T<sub>J</sub> = 70°C**

I/O Module Input Propagation Delays		–3 Speed <sup>1</sup>		–2 Speed <sup>1</sup>		–1 Speed		Std. Speed		3.3 V Speed <sup>1</sup>		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t <sub>INY</sub>	Input Data Pad to Y		2.8		3.2		3.6		4.2		5.5	ns
t <sub>ICKY</sub>	Input Reg IOCLK Pad to Y		4.7		5.3		6.0		7.0		9.2	ns
t <sub>OCKY</sub>	Output Reg IOCLK Pad to Y		4.7		5.3		6.0		7.0		9.2	ns
t <sub>ICLRY</sub>	Input Asynchronous Clear to Y		4.7		5.3		6.0		7.0		9.2	ns
t <sub>OCLRY</sub>	Output Asynchronous Clear to Y		4.7		5.3		6.0		7.0		9.2	ns
<b>Predicted Input Routing Delays<sup>2</sup></b>												
t <sub>RD1</sub>	FO = 1 Routing Delay		0.9		1.0		1.1		1.3		1.7	ns
t <sub>RD2</sub>	FO = 2 Routing Delay		1.2		1.4		1.6		1.8		2.4	ns
t <sub>RD3</sub>	FO = 3 Routing Delay		1.4		1.6		1.8		2.1		2.8	ns
t <sub>RD4</sub>	FO = 4 Routing Delay		1.7		1.9		2.2		2.5		3.3	ns
t <sub>RD8</sub>	FO = 8 Routing Delay		2.8		3.2		3.6		4.2		5.5	ns
<b>I/O Module Sequential Timing (wrt IOCLK pad)</b>												
t <sub>INH</sub>	Input F-F Data Hold	0.0		0.0		0.0		0.0		0.0		ns
t <sub>INSU</sub>	Input F-F Data Setup	1.8		2.0		2.3		2.7		3.0		ns
t <sub>IDEH</sub>	Input Data Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t <sub>IDESU</sub>	Input Data Enable Setup	5.8		6.5		7.5		8.6		8.6		ns
t <sub>OUTH</sub>	Output F-F Data hold	0.7		0.8		0.9		1.0		1.0		ns
t <sub>OUTSU</sub>	Output F-F Data Setup	0.7		0.8		0.9		1.0		1.0		ns
t <sub>ODEH</sub>	Output Data Enable Hold	0.3		0.4		0.4		0.5		0.5		ns
f <sub>ODESU</sub>	Output Data Enable Setup	1.3		1.5		1.7		2.0		2.0		ns

Notes: \*

1. The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at <http://www.microsemi.com/soc/support/notifications/default.aspx#pdn>.
2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.

## A1425A, A14V25A Timing Characteristics (continued)

Table 2-24 • A1425A, A14V25A Worst-Case Commercial Conditions, VCC = 4.75 V, T<sub>J</sub> = 70°C

I/O Module – TTL Output Timing <sup>1</sup>		–3 Speed <sup>2</sup>		–2 Speed <sup>2</sup>		–1 Speed		Std. Speed		3.3 V Speed <sup>1</sup>		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t <sub>DHS</sub>	Data to Pad, High Slew		5.0		5.6		6.4		7.5		9.8	ns
t <sub>DLS</sub>	Data to Pad, Low Slew		8.0		9.0		10.2		12.0		15.6	ns
t <sub>ENZHS</sub>	Enable to Pad, Z to H/L, High Slew		4.0		4.5		5.1		6.0		7.8	ns
t <sub>ENZLS</sub>	Enable to Pad, Z to H/L, Low Slew		7.4		8.3		9.4		11.0		14.3	ns
t <sub>ENHSZ</sub>	Enable to Pad, H/L to Z, High Slew		6.5		7.5		8.5		10.0		13.0	ns
t <sub>ENLSZ</sub>	Enable to Pad, H/L to Z, Low Slew		6.5		7.5		8.5		10.0		13.0	ns
t <sub>CKHS</sub>	IOCLK Pad to Pad H/L, High Slew		7.5		7.5		9.0		10.0		13.0	ns
t <sub>CKLS</sub>	IOCLK Pad to Pad H/L, Low Slew		11.3		11.3		13.5		15.0		19.5	ns
d <sub>TLHHS</sub>	Delta Low to High, High Slew		0.02		0.02		0.03		0.03		0.04	ns/pF
d <sub>TLHLS</sub>	Delta Low to High, Low Slew		0.05		0.05		0.06		0.07		0.09	ns/pF
d <sub>THLHS</sub>	Delta High to Low, High Slew		0.04		0.04		0.04		0.05		0.07	ns/pF
d <sub>THLLS</sub>	Delta High to Low, Low Slew		0.05		0.05		0.06		0.07		0.09	ns/pF
I/O Module – CMOS Output Timing <sup>1</sup>												
t <sub>DHS</sub>	Data to Pad, High Slew		6.2		7.0		7.9		9.3		12.1	ns
t <sub>DLS</sub>	Data to Pad, Low Slew		11.7		13.1		14.9		17.5		22.8	ns
t <sub>ENZHS</sub>	Enable to Pad, Z to H/L, High Slew		5.2		5.9		6.6		7.8		10.1	ns
t <sub>ENZLS</sub>	Enable to Pad, Z to H/L, Low Slew		8.9		10.0		11.3		13.3		17.3	ns
t <sub>ENHSZ</sub>	Enable to Pad, H/L to Z, High Slew		6.7		7.5		8.5		10.0		13.0	ns
t <sub>ENLSZ</sub>	Enable to Pad, H/L to Z, Low Slew		6.7		7.5		9.0		10.0		13.0	ns
t <sub>CKHS</sub>	IOCLK Pad to Pad H/L, High Slew		8.9		8.9		10.7		11.8		15.3	ns
t <sub>CKLS</sub>	IOCLK Pad to Pad H/L, Low Slew		13.0		13.0		15.6		17.3		22.5	ns
d <sub>TLHHS</sub>	Delta Low to High, High Slew		0.04		0.04		0.05		0.06		0.08	ns/pF
d <sub>TLHLS</sub>	Delta Low to High, Low Slew		0.07		0.08		0.09		0.11		0.14	ns/pF
d <sub>THLHS</sub>	Delta High to Low, High Slew		0.03		0.03		0.03		0.04		0.05	ns/pF
d <sub>THLLS</sub>	Delta High to Low, Low Slew		0.04		0.04		0.04		0.05		0.07	ns/pF

Notes: \*

1. Delays based on 35 pF loading.
2. The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at <http://www.microsemi.com/soc/support/notifications/default.aspx#pdn>.

## A1460A, A14V60A Timing Characteristics (continued)

**Table 2-33 • A1460A, A14V60A Worst-Case Commercial Conditions, VCC = 4.75 V, T<sub>J</sub> = 70°C**

Dedicated (hardwired) I/O Clock Network		–3 Speed <sup>1</sup>		–2 Speed <sup>1</sup>		–1 Speed		Std. Speed		3.3 V Speed <sup>1</sup>		Units
Parameter/Description		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t <sub>IOCKH</sub>	Input Low to High (pad to I/O module input)		2.3		2.6		3.0		3.5		4.5	ns
t <sub>IOPWH</sub>	Minimum Pulse Width High	2.4		3.2		3.8		4.8		6.5		ns
t <sub>IPOWL</sub>	Minimum Pulse Width Low	2.4		3.2		3.8		4.8		6.5		ns
t <sub>IOSAPW</sub>	Minimum Asynchronous Pulse Width	2.4		3.2		3.8		4.8		6.5		ns
t <sub>IOCKSW</sub>	Maximum Skew		0.6		0.6		0.6		0.6		0.6	ns
t <sub>IOP</sub>	Minimum Period	5.0		6.8		8.0		10.0		13.4		ns
f <sub>IOMAX</sub>	Maximum Frequency		200		150		125		100		75	MHz
<b>Dedicated (hardwired) Array Clock</b>												
t <sub>HCKH</sub>	Input Low to High (pad to S-module input)		3.7		4.1		4.7		5.5		7.0	ns
t <sub>HCKL</sub>	Input High to Low (pad to S-module input)		3.7		4.1		4.7		5.5		7.0	ns
t <sub>HPWH</sub>	Minimum Pulse Width High	2.4		3.2		3.8		4.8		6.5		ns
t <sub>HPWL</sub>	Minimum Pulse Width Low	2.4		3.2		3.8		4.8		6.5		ns
t <sub>HCKSW</sub>	Delta High to Low, Low Slew		0.6		0.6		0.6		0.6		0.6	ns
t <sub>HP</sub>	Minimum Period	5.0		6.8		8.0		10.0		13.4		ns
f <sub>HMAX</sub>	Maximum Frequency		200		150		125		100		75	MHz
<b>Routed Array Clock Networks</b>												
t <sub>RCKH</sub>	Input Low to High (FO = 64)		6.0		6.8		7.7		9.0		11.8	ns
t <sub>RCKL</sub>	Input High to Low (FO = 64)		6.0		6.8		7.7		9.0		11.8	ns
t <sub>RPWH</sub>	Min. Pulse Width High (FO = 64)	4.1		4.5		5.4		6.1		8.2		ns
t <sub>RPWL</sub>	Min. Pulse Width Low (FO = 64)	4.1		4.5		5.4		6.1		8.2		ns
t <sub>RCKSW</sub>	Maximum Skew (FO = 128)		1.2		1.4		1.6		1.8		1.8	ns
t <sub>RP</sub>	Minimum Period (FO = 64)	8.3		9.3		11.1		12.5		16.7		ns
f <sub>RMAX</sub>	Maximum Frequency (FO = 64)		120		105		90		80		60	MHz
<b>Clock-to-Clock Skews</b>												
t <sub>IOHCKSW</sub>	I/O Clock to H-Clock Skew	0.0	2.6	0.0	2.7	0.0	2.9	0.0	3.0	0.0	3.0	ns
t <sub>IORCKSW</sub>	I/O Clock to R-Clock Skew (FO = 64) (FO = 216)	0.0	1.7	0.0	1.7	0.0	1.7	0.0	1.7	0.0	5.0	ns
		0.0	5.0	0.0	5.0	0.0	5.0	0.0	5.0	0.0	5.0	
t <sub>HRCKSW</sub>	H-Clock to R-Clock Skew (FO = 64) (FO = 216)	0.0	1.3	0.0	1.0	0.0	1.0	0.0	1.0	0.0	1.0	ns
		0.0	3.0	0.0	3.0	0.0	3.0	0.0	3.0	0.0	3.0	

**Notes:**

1. The –2 and –3 speed grades have been discontinued. Refer to PDN 0104, PDN 0203, PDN 0604, and PDN 1004 at <http://www.microsemi.com/soc/support/notifications/default.aspx#pdn>.
2. Delays based on 35 pF loading.



## Pin Descriptions

### **CLKA**                      **Clock A (Input)**

Clock input for clock distribution networks. The Clock input is buffered prior to clocking the logic modules. This pin can also be used as an I/O.

### **CLKB**                      **Clock B (Input)**

Clock input for clock distribution networks. The Clock input is buffered prior to clocking the logic modules. This pin can also be used as an I/O.

### **GND**                      **Ground**

LOW supply voltage.

### **HCLK**                      **Dedicated (Hard-wired) Array Clock (Input)**

Clock input for sequential modules. This input is directly wired to each S-Module and offers clock speeds independent of the number of S-Modules being driven. This pin can also be used as an I/O.

### **I/O**                      **Input/Output (Input, Output)**

The I/O pin functions as an input, output, three-state, or bidirectional buffer. Input and output levels are compatible with standard TTL and CMOS specifications. Unused I/O pins are tristated by the Designer Series software.

### **IOCLK**                      **Dedicated (Hard-wired) I/O Clock (Input)**

Clock input for I/O modules. This input is directly wired to each I/O module and offers clock speeds independent of the number of I/O modules being driven. This pin can also be used as an I/O.

### **IOPCL**                      **Dedicated (Hard-wired) I/O Preset/Clear (Input)**

Input for I/O preset or clear. This global input is directly wired to the preset and clear inputs of all I/O registers. This pin functions as an I/O when no I/O preset or clear macros are used.

### **MODE**                      **Mode (Input)**

The MODE pin controls the use of diagnostic pins (DCLK, PRA, PRB, SDI). When the MODE pin is HIGH, the special functions are active. When the MODE pin is LOW, the pins function as I/Os. To provide Actionprobe capability, the MODE pin should be terminated to GND through a 10K resistor so that the MODE pin can be pulled high when required.

### **NC**                      **No Connection**

This pin is not connected to circuitry within the device.

### **PRA**                      **Probe A (Output)**

The Probe A pin is used to output data from any user-defined design node within the device. This independent diagnostic pin can be used in conjunction with the Probe B pin to allow real-time diagnostic output of any signal path within the device. The Probe A pin can be used as a user-defined I/O when debugging has been completed. The pin's probe capabilities can be permanently disabled to protect programmed design confidentiality. PRA is accessible when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW.

### **PRB**                      **Probe B (Output)**

The Probe B pin is used to output data from any user-defined design node within the device. This independent diagnostic pin can be used in conjunction with the Probe A pin to allow real-time diagnostic output of any signal path within the device. The Probe B pin can be used as a user-defined I/O when debugging has been completed. The pin's probe capabilities can be permanently disabled to protect programmed design confidentiality. PRB is accessible when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW.

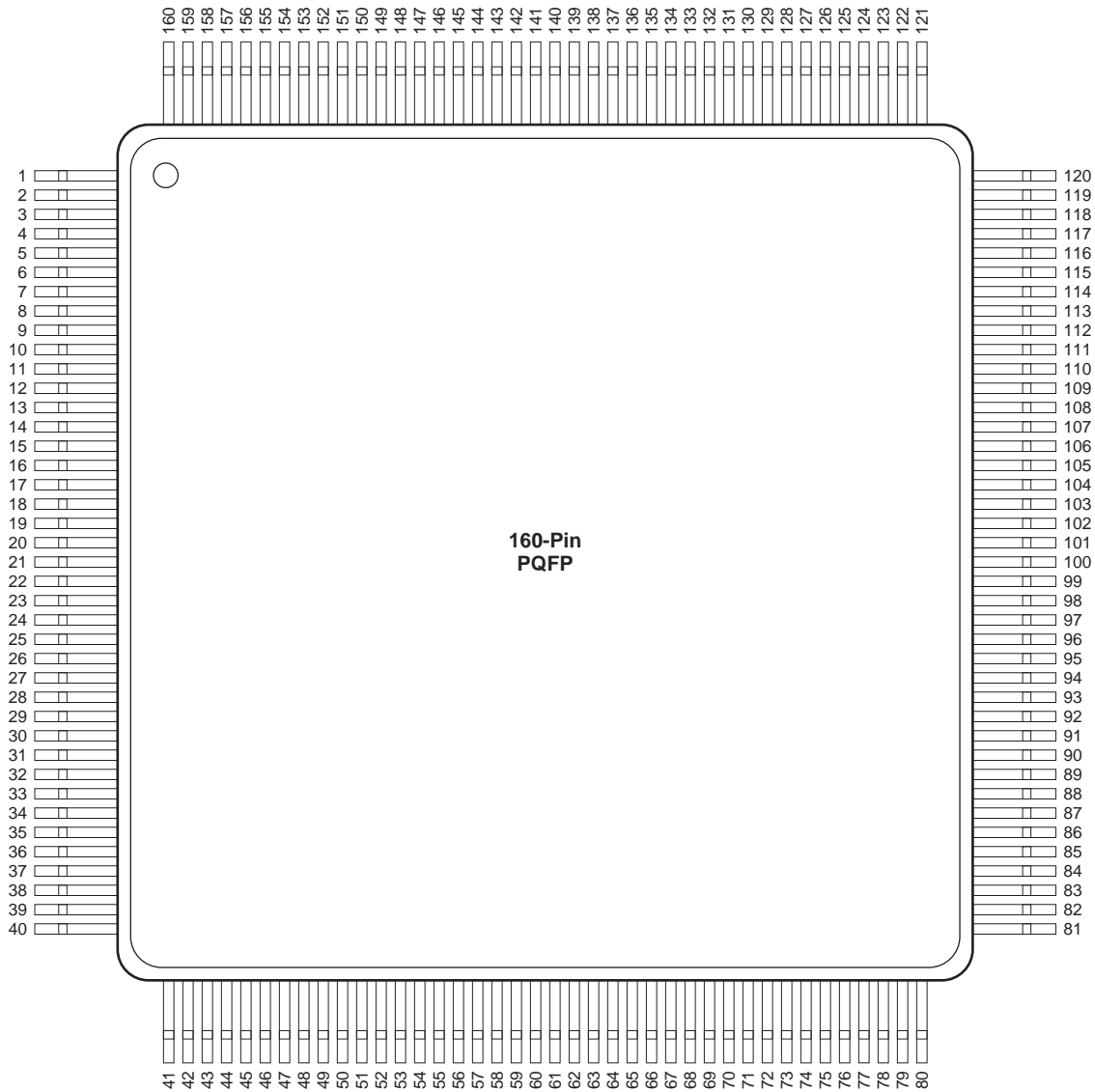
### **SDI**                      **Serial Data Input (Input)**

Serial data input for diagnostic probe and device programming. SDI is active when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW.





## PQ160



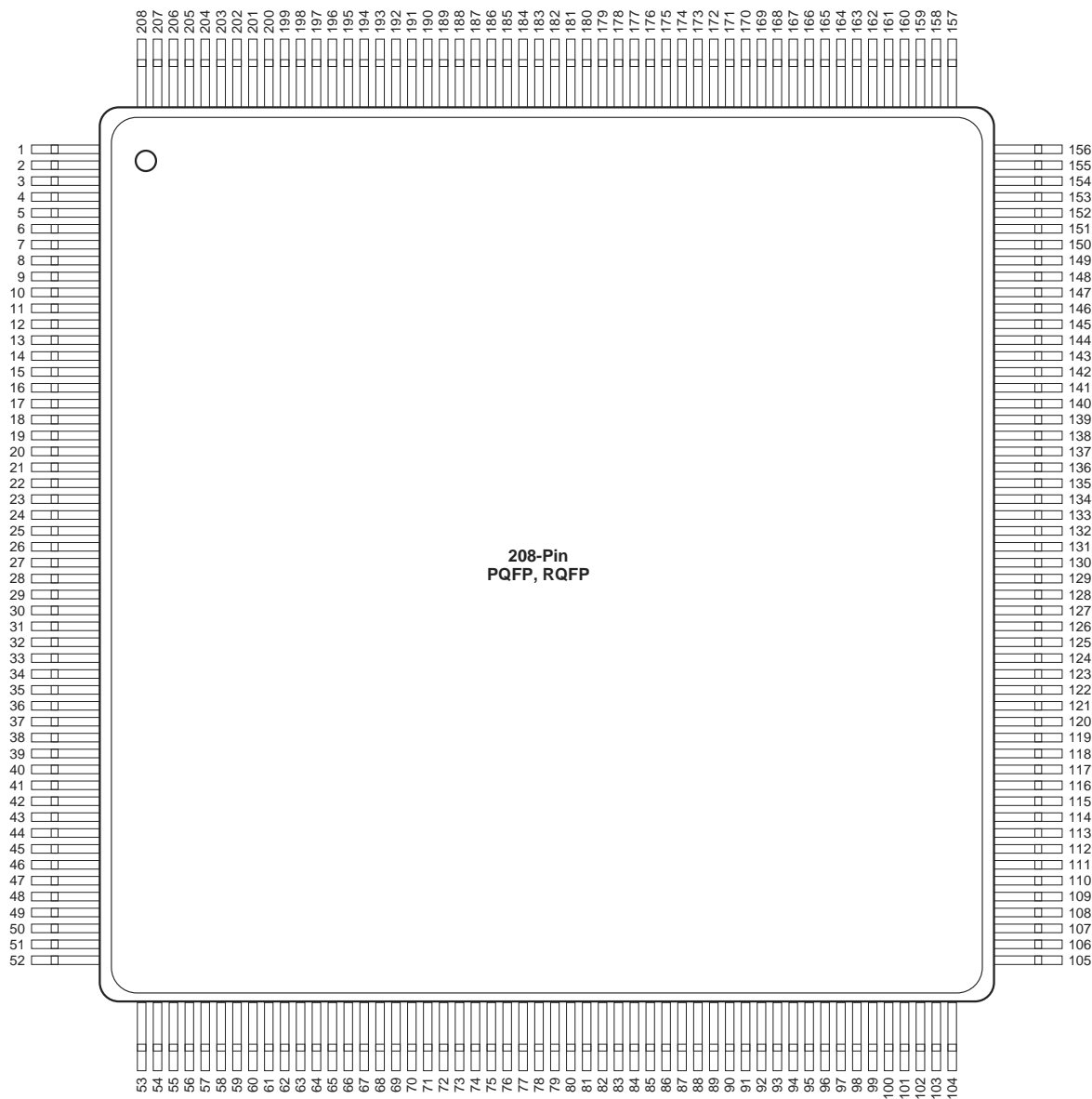
*Note:* This is the top view of the package

### Note

For Package Manufacturing and Environmental information, visit the Resource Center at <http://www.microsemi.com/soc/products/solutions/package/docs.aspx>

PQ160			
Pin Number	A1425, A14V25 Function	A1440, A14V40 Function	A1460, A14V60 Function
1	GND	GND	GND
2	SDI, I/O	SDI, I/O	SDI, I/O
5	NC	I/O	I/O
9	MODE	MODE	MODE
10	VCC	VCC	VCC
14	NC	I/O	I/O
15	GND	GND	GND
18	VCC	VCC	VCC
19	GND	GND	GND
20	NC	I/O	I/O
24	NC	I/O	I/O
27	NC	I/O	I/O
28	VCC	VCC	VCC
29	VCC	VCC	VCC
40	GND	GND	GND
41	NC	I/O	I/O
43	NC	I/O	I/O
45	NC	I/O	I/O
46	VCC	VCC	VCC
47	NC	I/O	I/O
49	NC	I/O	I/O
51	NC	I/O	I/O
53	NC	I/O	I/O
58	PRB, I/O	PRB, I/O	PRB, I/O
59	GND	GND	GND
60	VCC	VCC	VCC
62	HCLK, I/O	HCLK, I/O	HCLK, I/O
63	GND	GND	GND
74	NC	I/O	I/O
75	VCC	VCC	VCC
76	NC	I/O	I/O
77	NC	I/O	I/O
78	NC	I/O	I/O
79	SDO	SDO	SDO
80	IOPCL, I/O	IOPCL, I/O	IOPCL, I/O
81	GND	GND	GND
90	VCC	VCC	VCC
91	VCC	VCC	VCC

## PQ208, RQ208



*Note:* This is the top view of the package

### Note

For Package Manufacturing and Environmental information, visit the Resource Center at <http://www.microsemi.com/soc/products/solutions/package/docs.aspx>

TQ176			TQ176		
Pin Number	A1440, A14V40 Function	A1460, A14V60 Function	Pin Number	A1440, A14V40 Function	A1460, A14V60 Function
1	GND	GND	89	GND	GND
2	SDI, I/O	SDI, I/O	98	VCC	VCC
10	MODE	MODE	99	VCC	VCC
11	VCC	VCC	108	GND	GND
20	NC	I/O	109	VCC	VCC
21	GND	GND	110	GND	GND
22	VCC	VCC	119	NC	I/O
23	GND	GND	121	NC	I/O
32	VCC	VCC	122	VCC	VCC
33	VCC	VCC	123	GND	GND
44	GND	GND	124	VCC	VCC
49	NC	I/O	132	IOCLK, I/O	IOCLK, I/O
51	NC	I/O	133	GND	GND
63	NC	I/O	138	NC	I/O
64	PRB, I/O	PRB, I/O	152	CLKA, I/O	CLKA, I/O
65	GND	GND	153	CLKB, I/O	CLKB, I/O
66	VCC	VCC	154	VCC	VCC
67	VCC	VCC	155	GND	GND
69	HCLK, I/O	HCLK, I/O	156	VCC	VCC
82	NC	I/O	157	PRA, I/O	PRA, I/O
83	NC	I/O	158	NC	I/O
87	SDO	SDO	170	NC	I/O
88	IOPCL, I/O	IOPCL, I/O	176	DCLK, I/O	DCLK, I/O

*Notes:*

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.

CQ256	
Pin Number	A14100 Function
1	GND
2	SDI, I/O
11	MODE
28	VCC
29	GND
30	VCC
31	GND
46	VCC
59	GND
90	PRB, I/O
91	GND
92	VCC
93	GND
94	VCC
96	HCLK, I/O
110	GND
126	SDO
127	IOPCL, I/O
128	GND

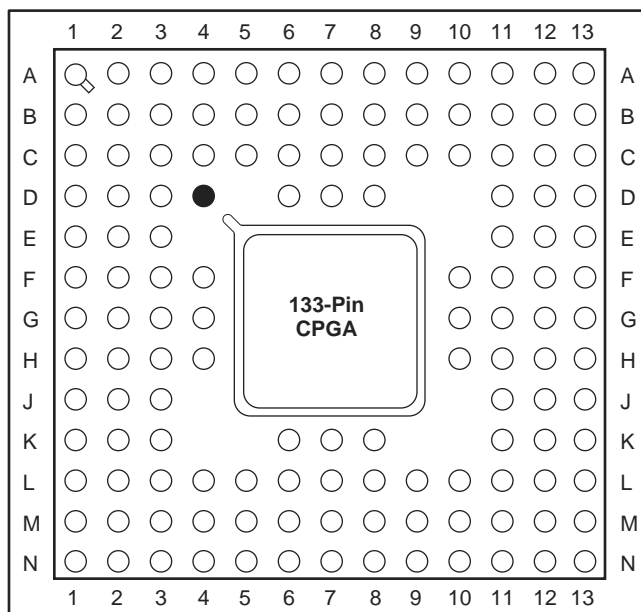
CQ256	
Pin Number	A14100 Function
141	VCC
158	GND
159	VCC
160	GND
161	VCC
174	VCC
175	GND
176	GND
188	IOCLK, I/O
189	GND
219	CLKA, I/O
220	CLKB, I/O
221	VCC
222	GND
223	VCC
224	GND
225	PRA, I/O
240	GND
256	DCLK, I/O

**Notes:**

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.



## PG133



*Note:* This is the top view.

### **Note**

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PG133	
A1425 Function	Location
CLKA or I/O	D7
CLKB or I/O	B6
DCLK or I/O	D4
GND	A2, C3, C7, C11, C12, F10, G3, G11, L3, L7, L11, M3, N12
HCLK or I/O	K7
IOCLK or I/O	C10
IOPCL or I/O	L10
MODE	E3
NC	A1, A7, A13, G1, G13, N1, N7, N13
PRA or I/O	A6
PRB or I/O	L6
SDI or I/O	C2
SDO	M11
VCC	B2, B7, B12, E11, G2, G12, J2, J12, M2, M7, M12

*Notes:*

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.
4. The PG133 package has been discontinued.

PG207	
A1460 Function	Location
CLKA or I/O	K1
CLKB or I/O	J3
DCLK or I/O	E4
GND	C14, D4, D5, D9, D14, J4, J14, P3, P4, P7, P9, P14, R15
HCLK or I/O	J15
IOCLK or I/O	P5
IOPCL or I/O	N14
MODE	D7
NC	A1, A2, A16, A17, B1, B17, C1, C2, S1, S3, S17, T1, T2, T16, T17
PRA or I/O	H1
PRB or I/O	K16
SDI or I/O	C3
SDO	P15
VCC	B2, B9, B16, D11, J2, J16, P12, S2, S9, S16, T5

**Notes:**

1. All unlisted pin numbers are user I/Os.
2. NC denotes no connection.
3. MODE should be terminated to GND through a 10K resistor to enable Actionprobe usage; otherwise it can be terminated directly to GND.



Revision	Changes	Page
Revision 2 (continued)	In the "Package Pin Assignments" section, notes were added to the pin tables for the following packages, stating that they are discontinued: "BG225" "PG100" "PG133" "PG175"	3-20 3-24 3-26 3-28
Revision 1 (June 2006)	RoHS compliant information was added to the "Ordering Information" section.	II